Notice of References Cited	Application/Control No. 10/849,743	Applicant(s)/Patent Under Reexamination MACNEILLE ET AL.	
	Examiner CUONG H. NGUYEN	Art Unit 3661	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,983,027	01-2006	Seki et al.	375/316
*	B	US-6,726,297	04-2004	Uesugi, Mitsuru	375/260
*	C	US-6,567,374	05-2003	Bohnke et al.	370/203
*	D	US-2005/0273258	12-2005	MacNeille et al.	701/300
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Experimental characterization of the nonlinear behavior of RF amplifiers, Rolain, Y.; Van Moer, W.; Pintelon, R.; Schoukens, J.; Microwave Theory and Techniques, IEEE Transactions on, Volume 54, Issue 8, Aug. 2006 Page(s):3209 - 3218, Digital Object Identifier 10.1109/TMTT.2006.879168
*	V	Broadband MIMO-OFDM wireless communications, Stuber, G.L.; Barry, J.R.; McLaughlin, S.W.; Ye Li; Ingram, M.A.; Pratt, T.G.; Proceedings of the IEEE, Volume 92, Issue 2, Feb 2004 Page(s):271 - 294, Digital Object Identifier 10.1109/JPROC.2003.821912
*	W	Doppler and frequency-offset synchronization in wideband OFDM, Salberg, A.-B.; Swami, A.; Wireless Communications, IEEE Transactions on, Volume 4, Issue 6, Nov. 2005 Page(s):2870 - 2881, Digital Object Identifier 10.1109/TWC.2005.858337
*	X	Optimal space-frequency Group codes for MIMO-OFDM system, Yao Chen; Aktas, E.; Tureli, U.; Communications, IEEE Transactions on, Volume 54, Issue 3, March 2006 Page(s):553 - 562, Digital Object Identifier 10.1109/TCOMM.2006.869781

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/849,743	Applicant(s)/Patent Under Reexamination MACNEILLE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	P. Banelli, "Theoretical analysis and performance of OFDM signals in nonlinear fading channels," IEEE Trans. Wireless Commun., vol. 2, no. 2, pp. 284–293, Mar. 2003.
*	V	R. Pintelon and J. Schoukens, System Identification: A Frequency Domain Approach. Piscataway, NJ: IEEE Press, 2001.
*	W	J. Schoukens, T. Dobrowiecki, and R. Pintelon, "Parametric identification of linear systems in the presence of nonlinear distortions. A frequency domain approach," IEEE Trans. Autom. Contr., vol. 43, no. 2, pp. 176–190, Feb. 1998.
*	X	I. Kollár, J. Schoukens, R. Pintelon, G. Simon, and G. Román, "Extension for the frequency domain system identification toolbox for MATLAB: Graphical user interface, objects, improved numerical, stability," in Proc. 12th IFAC Syst. Identification Symp., Santa Barbara, CA, Jun. 21–23, 2000, vol. 2, pp. 699–702.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/849,743	Applicant(s)/Patent Under Reexamination MACNEILLE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Unknown author, "Measurement of frequency response functions using periodic excitations, corrupted by correlated input/output errors," IEEE Trans. Instrum. Meas., vol. 50, no. 6, pp. 1753–1760, Jun. 2001, cited by others.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.